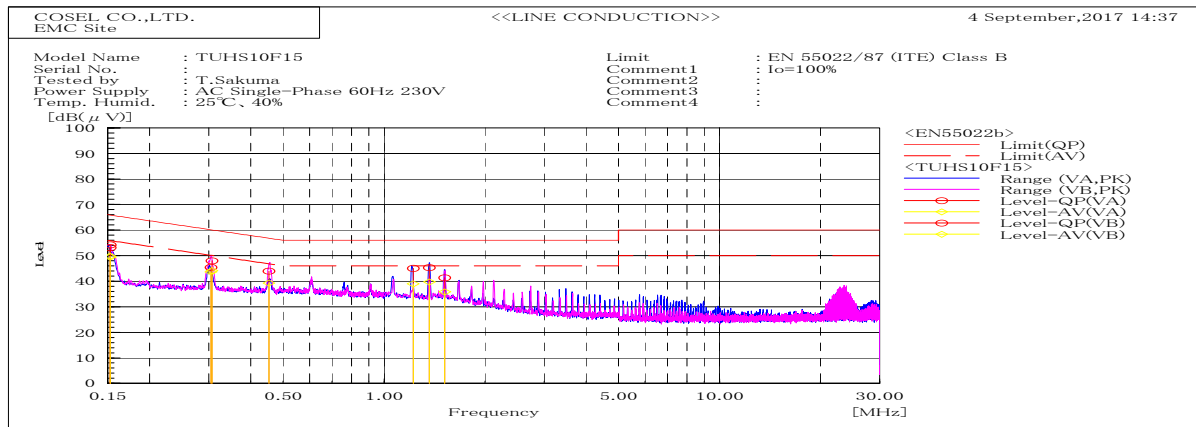
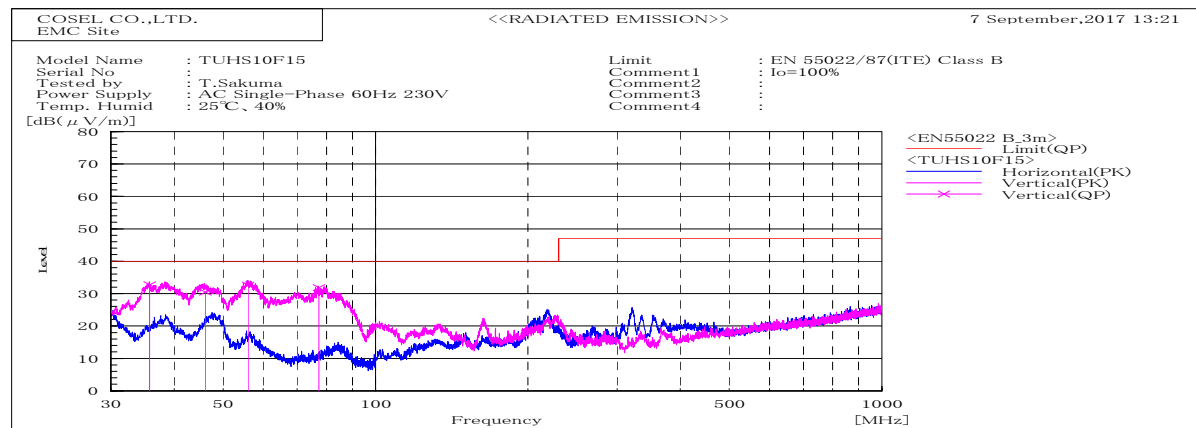


DATA SHEET		Date	12-Sep-17
Model	TUHS10F15	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



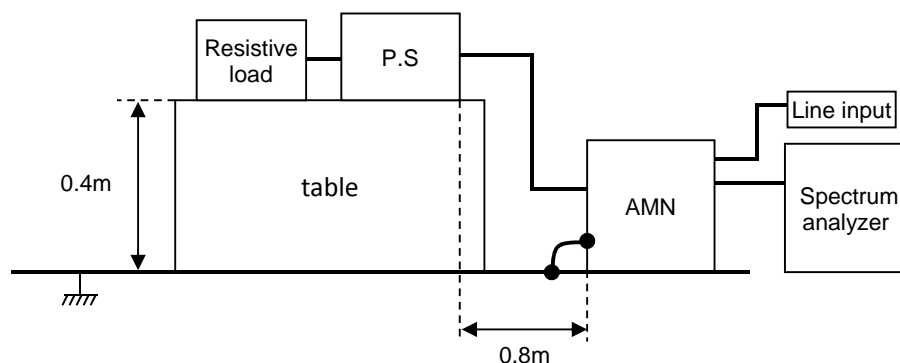
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV/m)		Limit dB(uV/m)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15241		VA	32.1	28.4	21.0	53.1	49.4	65.9	55.9	12.8	6.5	Pass	
0.15242		VB	33.2	28.8	21.0	54.2	49.8	65.9	55.9	11.7	6.1	Pass	
0.30465		VA	24.5	22.8	20.9	45.4	43.7	60.1	50.1	14.7	6.4	Pass	
0.30686		VB	27.1	23.2	20.9	48.0	44.1	60.1	50.1	12.1	6.0	Pass	
0.45357		VB	23.0	18.4	20.9	43.9	39.3	56.8	46.8	12.9	7.5	Pass	
1.22118		VA	24.0	17.9	21.0	45.0	38.9	56.0	46.0	11.0	7.1	Pass	
1.36567		VA	24.3	18.7	21.0	45.3	39.7	56.0	46.0	10.7	6.3	Pass	
1.51656		VB	20.3	14.8	21.0	41.3	35.8	56.0	46.0	14.7	10.2	Pass	



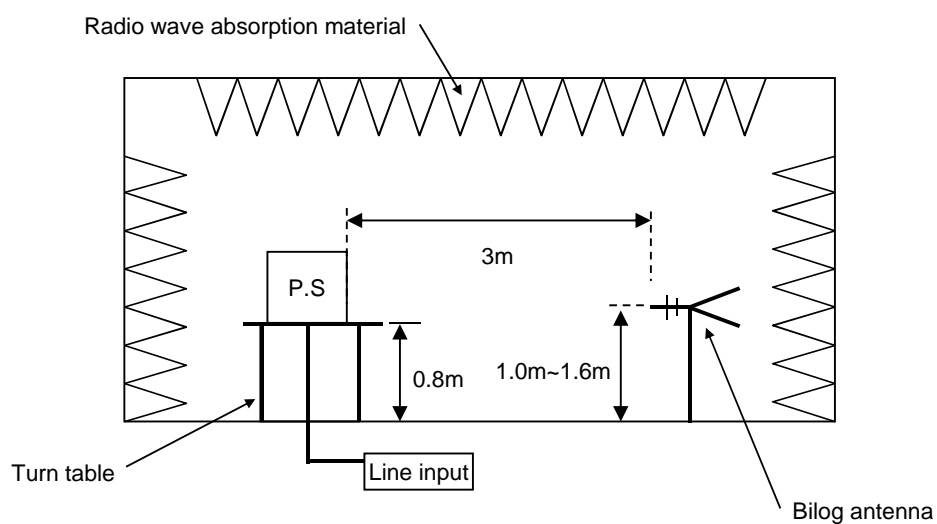
Frequency MHz	Polarization	Stability	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
35.795	V	Stable	42.8		-10.1	32.7	40.0	7.3	Pass	105	313	
46.121	V	Stable	48.9		-18.5	30.4	40.0	9.6	Pass	100	317	
55.996	V	Stable	53.2		-20.6	32.6	40.0	7.4	Pass	103	359	
77.248	V	Stable	48.5		-16.7	31.8	40.0	8.2	Pass	103	334	

DATA SHEET		Date	12-Sep-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

1. Line conduction



2. Radiated emission



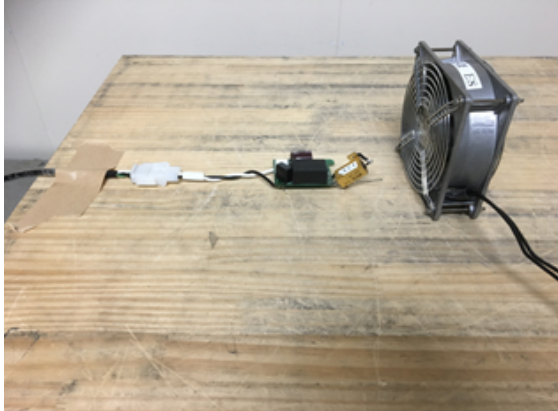
Conditions

Test: EMI

Model Name: TUHS10F15

○ Photographs of Test Set-Up

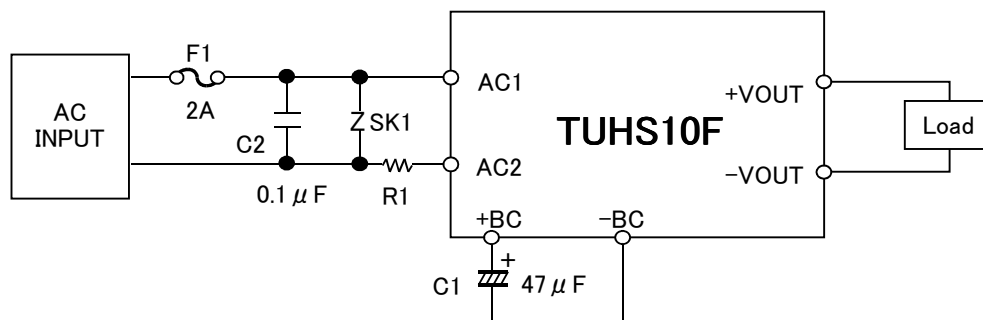
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1:	SLT250V2A (Nippon Seisen)	2A
R1:	2K100JA (TAMURA THERMAL DEVICE)	10 Ω
SK1:	S10K385E2K1 (TDK EPCOS)	

Fig.1 Testing circuitry